

L Number	Hits	Search Text	DB	Time stamp
1	17	self-aligned adj metal adj contact	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/19 10:03
2	13	"6365453"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/19 10:04



- ☐ BRS: lower
- ☐ BRS: 4 and
- ☐ BRS: no impurit
- ☐ BRS:
- ☐ BRS: wafer
- ☐ BRS: ferromagnetic and offset
- ☐ BRS: 1 2
- ☐ BRS:
- ☐ BRS:
- ☐ BRS: upside
- ☐ Pending
- ☒ Active
- ☐ L1: (17) self-aligned adj metal adj contact
- ☒ L2: (13) "6365453"

USPAT, USAPUB, EPO, JPO, DERWENT, INL, TDB

Default operator: DR

"6365453"

☐ Push
☒ Highlight all hit terms initially

ALL BRS Items ALL US Pat Items Images Text HTML

	U	I	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval Cla	Inventor	S	C	P	3	Image Do
1	<input type="checkbox"/>	<input type="checkbox"/>	US 20030015750 A1	20030123	15	Structure for reducing contact aspect ratios	257/301	257/E21.011; 257/E21.59;		Deboer, Scott J. et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 200300
2	<input type="checkbox"/>	<input type="checkbox"/>	US 20020195639 A1	20021226	15	Method and structure for reducing contact aspect ratios	257/301	257/E21.011; 257/E21.59;		Deboer, Scott J. et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 200201
3	<input type="checkbox"/>	<input type="checkbox"/>	US 6683339 B2	20040127	12	Semiconductor memory device having metal contact structure	257/296	257/208; 257/209;		Suh, Chunsuk	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 668333
4	<input type="checkbox"/>	<input type="checkbox"/>	US 6677636 B2	20040113	15	Structure for reducing contact aspect ratios	257/306	257/301; 257/303;		Deboer, Scott J. et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 667763
5	<input type="checkbox"/>	<input type="checkbox"/>	US 6670238 B2	20031230	15	Method and structure for reducing contact aspect ratios	438/255	257/E21.011; 257/E21.59;		Deboer, Scott J. et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 667023
6	<input type="checkbox"/>	<input type="checkbox"/>	US 6649483 B2	20031118	10	Method for fabricating a capacitor configuration	438/393			Hartner, Walter et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 664948
7	<input type="checkbox"/>	<input type="checkbox"/>	US 6642097 B2	20031104	19	Structure for capacitor-top-plate to bit-line-contact overlay margin	438/241	438/253; 438/255		Tu, Kuo-Chi	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 664209
8	<input type="checkbox"/>	<input type="checkbox"/>	US 6469336 B2	20021022	15	Structure for reducing contact aspect ratios	257/301	257/E21.011; 257/E21.59;		Deboer, Scott J. et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 646933
9	<input type="checkbox"/>	<input type="checkbox"/>	US 6365453 B1	20020402	15	Method and structure for reducing contact aspect ratios	438/253	257/E21.011; 257/E21.59;		Deboer, Scott J. et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 636545
10	<input type="checkbox"/>	<input type="checkbox"/>	US 20030015750 A	20040113		Bit line contact forming structure for dynamic random access memory. chi				AGARWAL, V K et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	
11	<input type="checkbox"/>	<input type="checkbox"/>	US 20020195639 A	20021226		Integrated circuit for fabrication of dynamic random access memory. circ				AGARWAL, V K et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	
12	<input type="checkbox"/>	<input type="checkbox"/>	US 6365453 B	20020402		Bit line contact formation method for dynamic random access memory. inv				AGARWAL, V K et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	
13	<input type="checkbox"/>	<input type="checkbox"/>	US 20010045658 A	20011129		Bit line contact for dynamic random access memory. has lower. intermedi				AGARWAL, V K et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	

Ready Details HTML

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